

| L Number | Hits | Search Text | DB | Time stamp |
|----------|------|--|---|---------------------|
| 1 | 1169 | 714/738.ccls. | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:42 |
| 2 | 2 | (714/738.ccls.) and (integrated adj circuit\$1) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:45 |
| 3 | 2 | (714/738.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:43 |
| 4 | 15 | (integrated adj circuit\$1) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:47 |
| 5 | 2 | (714/733.ccls.) and (integrated adj circuit\$1) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:46 |
| 6 | 0 | (713/400.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:49 |
| 7 | 2 | (375/221.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:50 |
| 8 | 0 | (324/763.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:50 |
| 10 | 2 | (370/249.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 15:51 |